

<b>Notice of References Cited</b>	Application/Control No. 10/760,081	Applicant(s)/Patent Under Reexamination KAWATE ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0147629	08-2003	Kikuchi et al.	386/69
*	B	US-2003/0161615	08-2003	Tsumagari et al.	386/95
*	C	US-2002/0042834	04-2002	Kremens et al.	709/231
*	D	US-6,253,025	06-2001	Kitamura et al.	386/125
*	E	US-2007/0140657	06-2007	Ando et al.	386/095
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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